2.   (recited) The system of claim 1, wherein the functional blocks of the SMPW comprise structural arrays.

3.   (recited) The system of claim 1, wherein the SMPW is pre-fabricated up to a contact layer so that a user can customize and program different blocks of the SMPW to the user's requirements.

4.   (recited) The system of claim 1, wherein the IC design flow has a cycle time of approximately 1-3 months.

5.   (recited) The system of claim 1, wherein the functional blocks are chosen from a group comprising: metal programmable PLLs; master/slave DLLs; metal programmable I/O elements; sea of gates; memory; and high speed serial links.

6.   (recited) A component architecture for use in a streamlined integrated circuit (IC) design process comprising:

a plurality of sub-blocks targeted to specific applications, wherein the architecture is pre-fabricated up to a contact layer in order to allow a user to customize and program the sub-blocks to the user's requirements through metallization.

7.   (recited) The component architecture of claim 6, wherein the sub-blocks are structural arrays.

8.   (recited) The component architecture of claim 6, wherein the sub-blocks are chosen from a group comprising: metal programmable PLLs; master/slave DLLs; metal programmable I/O elements; sea of gates; memory; and high speed serial links

9.   (recited) A method for designing an integrated circuit (IC) comprising:

providing a plurality of structural multi-project wafers (SMPWs), each SMPW comprising a plurality of pre-manufactured and pre-validated functional blocks;

if one of the plurality of SMPWs meets an IC designer's requirements, proceeding to a streamlined design flow and production;

if one of the plurality of SMPWs is usable as an intermediate step, extracting usable SMPW component(s) for use in a normal COT flow; and

if one of the plurality of SMPWs does not meet a user's requirement and is not usable as an intermediate step, extracting any usable IP from the plurality of SMPWs for use in a normal COT flow.

10.   (recited) The method of claim 9, wherein the streamlined design flow has a cycle time of 1-3 months and wherein the normal COT design flow has a cycle time of 12-24 months.

11.   (recited) A method for providing integrated circuit design assistance comprising:

maintaining an inventory of structural multi-project wafers (SMPWs), each SMPW comprising a plurality of pre-manufactured and pre-validated functional blocks.

12.   (recited) A method as claimed in claim 11, wherein the functional blocks are metal programmable to a user's specific requirements.

13.   (recited) A method as claimed in claim 11, further comprising:

determining whether one of the inventory of SMPWs can meet all of a user's IC design requirements or can serve an intermediate step in a user's IC design process, such as market/concept validation or IP validation.

14.   (recited) A method as claimed in claim 13, further comprising:

determining whether any IP useful to a user's requirement is contained within the inventory of SMPWs.

15.   (recited) A method as claimed in claim 11, and further comprising:

reducing manufacturing costs to users by sharing the SMPWs among multiple users.

16.   (recited) A method as claimed in claim 11, and further comprising:

maintaining a pool of validated IP that is embodied in the inventory of SMPWs.

17.   (amended) A method as claimed in claim 16, and further comprising:

transferring an IP component from the pool of validated IP from [to] programmable logic

for use in COT flow.

18.   (recited) A method as claimed in claim 11, and further comprising:

facilitating migration to a COT flow with the inventory of SMPWs.

19.   (recited) A method as claimed in claim 11, and further comprising:

providing multiple packaging and assembly options for SMPW users.

20.   (recited) A method as claimed in claim 19, wherein the packaging and assembly

options are chosen from a group comprising: wire bond, flip chip, BGA, plastics and ceramics.

REMARKS

Applicants respectfully request that the foregoing amendments be entered before

examination of the above-captioned application.